

March 2008

FDP047N08

N-Channel PowerTrench[®] MOSFET 75V, 164A, 4.7m Ω

Features

- $R_{DS(on)} = 3.8 \text{m}\Omega \text{ (Typ.)} @ V_{GS} = 10 \text{V, } I_D = 80 \text{A}$
- · Fast switching speed
- · Low gate charge
- High performance trench technology for extremely low R_{DS(on)}
- High power and current handling capability
- RoHS compliant

Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

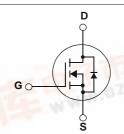
Application

• DC to DC convertors / Synchronous Rectification





G D S TO-220 FDP Series



MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

Symbol		Parameter		Ratings	Units
V _{DSS}	Drain to Source Voltage	An		75	V
V _{GSS}	Gate to Source Voltage			±20	V
" W(P)	Drain Current	-Continuous (T _C = 25°C)		164*	Α
D	DrainCurrent	-Continuous (T _C = 100°C)		116*	Α
I _{DM}	Drain Current	- Pulsed	(Note 1)	656	Α
E _{AS}	Single Pulsed Avalanche	Energy	(Note 2)	670	mJ
dv/dt	Peak Diode Recovery dv/	dt	(Note 3)	3.0	V/ns
D	Dawas Dissipation	$(T_C = 25^{\circ}C)$	LITE	268	W
P_{D}	Power Dissipation	- Derate above 25°C		1.79	W/°C
T _J , T _{STG}	Operating and Storage Te	mperature Range		-55 to +175	°С
Γ _L	Maximum Lead Temperat	ure for Soldering Purpose, nds		300	°C

^{*}Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 80A.

Thermal Characteristics

Symbol	Parameter	Ratings	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case 0.56		
$R_{\theta CS}$	Thermal Resistance, Case to Sink Typ. 0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	

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Package Marking and Ordering Information $T_C = 25^{\circ}C$ unless otherwise noted

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP047N08	FDP047N08	TO-220	-	-	50

Electrical Characteristics

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V, T_C = 25^{\circ} C$	75	-	-	V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I _D = 250μA, Referenced to 25°C	-	0.02	-	V/°C
	Zero Gate Voltage Drain Current	$V_{DS} = 75V, V_{GS} = 0V$	-	-	1	^
IDSS	Zero Gate voltage Drain Current	$V_{DS} = 75V, T_{C} = 150^{\circ}C$	-	-	500	μΑ
I _{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	±100	nA

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2.5	3.5	4.5	V
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 80A$	ı	3.7	4.7	mΩ
9 _{FS}	Forward Transconductance	$V_{DS} = 10V, I_D = 80A$ (Note 4)	ı	150	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	\\\\ 25\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\\	-	7080	9415	pF
C _{oss}	Output Capacitance	V _{DS} = 25V, V _{GS} = 0V f = 1MHz	-	870	1155	pF
C _{rss}	Reverse Transfer Capacitance	1 - 11/11/2	-	410	615	pF

Switching Characteristics

t _{d(on)}	Turn-On Delay Time			-	100	210	ns
t _r	Turn-On Rise Time	$V_{DD} = 37.5V, I_{D} = 80A$		-	147	304	ns
t _{d(off)}	Turn-Off Delay Time	$R_{GEN} = 25\Omega$, $V_{GS} = 10V$		-	220	450	ns
t _f	Turn-Off Fall Time	(Note	4, 5)	-	114	238	ns
Q _{g(tot)}	Total Gate Charge at 10V			-	117	152	nC
Q _{gs}	Gate to Source Gate Charge	$V_{DS} = 60V, I_{D} = 80A$		-	37	-	nC
Q _{gd}	Gate to Drain "Miller" Charge	V _{GS} = 10V (Note	4, 5)	-	32	-	nC

Drain-Source Diode Characteristics

IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	164	Α	
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	656	Α	
V_{SD}	Drain to Source Diode Forward Voltage	$V_{GS} = 0V, I_{SD} = 80A$		-	-	1.25	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0V, I_{SD} = 80A$		-	45	-	ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	(Note 4)	-	66	-	nC

- Notes:

 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L = 0.21mH, I_{AS} = 80A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25 $^{\circ}$ C
- 3. $I_{SD} \le 75 A$, di/dt $\le 200 A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$
- 4. Pulse Test: Pulse width $\leq 300 \mu s, \ Duty \ Cycle \leq 2\%$
- 5. Essentially Independent of Operating Temperature Typical Characteristics

Typical Performance Characteristics

Figure 1. On-Region Characteristics

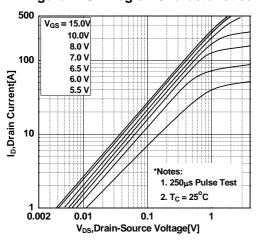


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

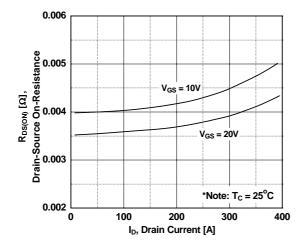


Figure 5. Capacitance Characteristics

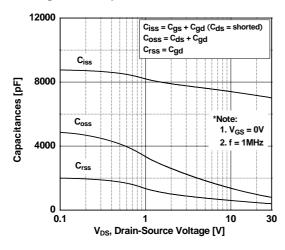


Figure 2. Transfer Characteristics

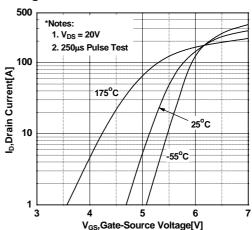


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

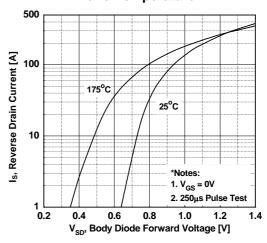
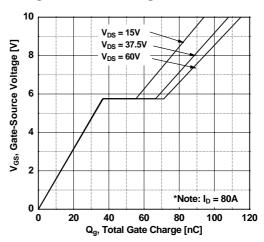


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

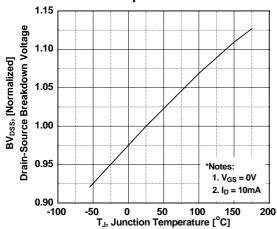


Figure 8. On-Resistance Variation vs. Temperature

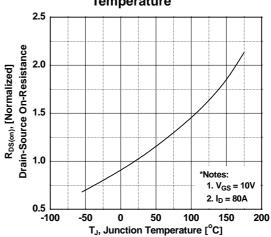


Figure 9. Maximum Safe Operating Area

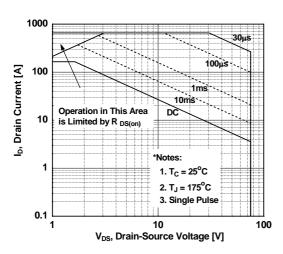


Figure 10. Maximum Drain Current vs. Case Temperature

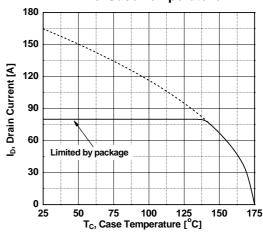
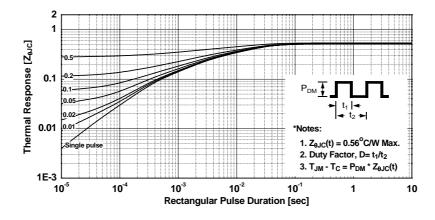
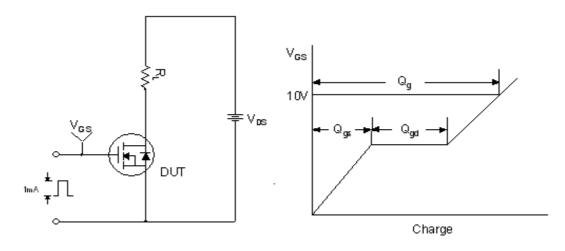


Figure 11. Transient Thermal Response Curve

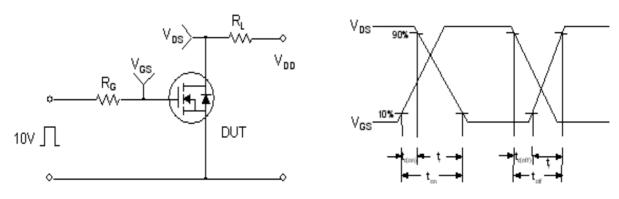


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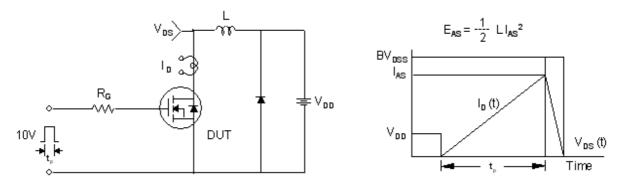
Gate Charge Test Circuit & Waveform



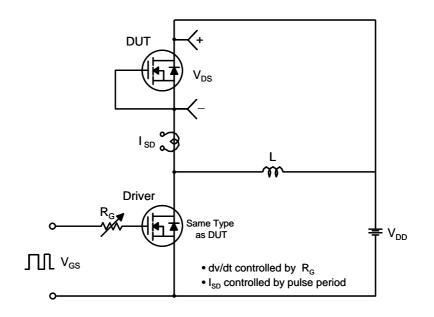
Resistive Switching Test Circuit & Waveforms

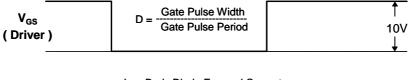


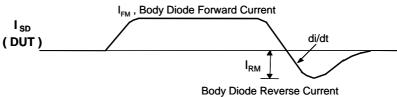
Unclamped Inductive Switching Test Circuit & Waveforms

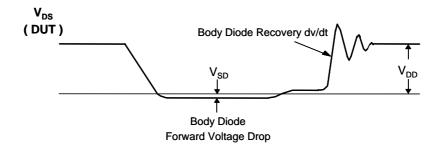


Peak Diode Recovery dv/dt Test Circuit & Waveforms



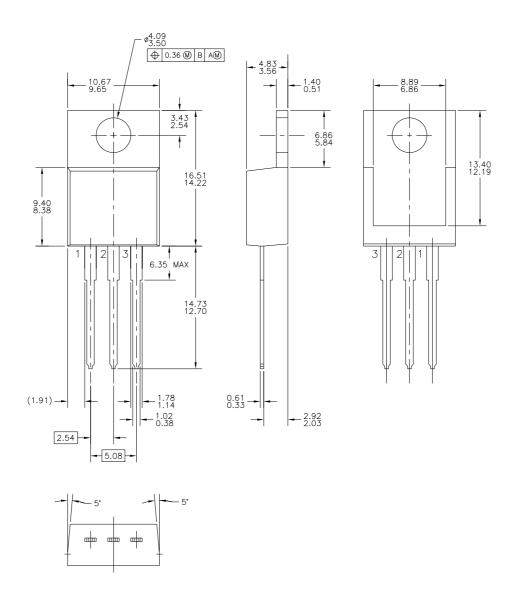






Mechanical Dimensions

TO-220







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